Allotted Date & Time: ____/____/______; _______AM   Date of form submission: ____________

HIGH RESOLUTION X-RAY DIFFRACTOMETRY REQUISITION FORM
CENTRAL RESEARCH FACILITY, NIT AGARTALA– 799046.

User's Name: ____________________________Roll No.: __________________Mob. No.: _______________

Contact Details: ____E-mail: __________________________

Supervisor's Name: ____Dept.: ___________________________

Analytical Requirements

I would like to get XRD data of________________ numbers of specimens (Metal / Ceramic / Polymer/Semiconductor) to analyse the sample of _____________________________________ (type: Thin Film or Powder) in the High Resolution XRD using Copper (Cu) target for the following examination / analysis using an appropriate mode:

PHASE ANALYSIS (2θ scan)   (2θ range __________to _________)

<u>At a time maximum 2 samples can be done.</u>

Declaration by the user

We are confident and also certify that the sample is **stable, non-volatile, non-toxic and is non-radioactive** by nature. I agree that my samples meet the above requirements. If the samples damage to the equipment due to incorrect information being provided, I will be responsible for it. **The results recorded, if communicated for publication, will acknowledge this facility at CRF.**

Payment of Rs.________________________(Measurement Charge + GST) has been paid through internet banking to Acc. Name: NIT Agartala - Project Fund & Acc. No: 30533908751(State Bank of India, IFS Code: SBIN0011491, Branch: NIT Agartala).

Please attach Bank Transaction Slip.

User's Sign.

Supervisor's Sign.

Sign of HOD (with date & seal)

Signature of Chairman (CRF)

Internal users please submit the filled and signed form to

Dr. Biswajit Saha,
Assistant Professor
Faculty In-charge (X-Ray Diffractometer) CRF
Department of Physics
Room No. 104 (New Building), NIT Agartala

NB: Sample must be dried and deposited at the lab one day before characterizations.